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IN THE CLAIMS

1. (Currently Amended) A thermal transfer material, comprising:

a heat spreader component, wherein the heat spreader component comprises a top surface, a bottom surface and at least one heat spreader material <u>and wherein the heat spreader component comprises a thickness of about 0.25 mm to about 6 mm</u>, and at least one solder material, wherein the solder material is directly deposited onto the bottom surface of the heat spreader component.

- 2. (Previously Presented) The thermal transfer material of claim 1, wherein the solder material is further coupled to a substrate.
- 3. (Previously Presented) The thermal transfer material of claim 2, wherein the substrate comprises silicon.
- 4. (Previously Presented) The thermal transfer material of claim 3, wherein the substrate is a metalized silicon die.
- 5. (Previously Presented) The thermal transfer material of claim 1, wherein the heat spreader component comprises a metal, metal-based material or combination thereof.
- 6. (Previously Presented) The thermal transfer material of claim 5, wherein the heat spreader component comprises nickel, aluminum, copper or a combination thereof.
- 7. (Previously Presented) The thermal transfer material of claim 5, wherein the metal-based material comprises silicon, carbon or a combination thereof.
- 8. Canceled.
- 9. (Currently Amended) The thermal transfer material of claim [[8]] 1, wherein the thickness is from about 1 mm to about 5 mm.
- 10. (Previously Presented) The thermal transfer material of claim 1, wherein the at least one solder material comprises a metal, a metal-based material or a combination thereof.

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11. (Previously Presented) The thermal transfer material of claim 10, wherein the metal comprises a transition metal.

- 12. (Previously Presented) The thermal transfer material of claim 11, wherein the metal comprises indium, tin, lead, silver, copper, antimony, tellurium or bismuth.
- 13. (Previously Presented) The thermal transfer material of claim 11, wherein the metal-based material comprises an alloy.
- 14. (Previously Presented) The thermal transfer material of claim 13, wherein the alloy comprises indium, tin, lead, silver, copper, antimony, tellurium, bismuth or a combination thereof.
- 15. (Previously Presented) The thermal transfer material of one of claims 12 or 13, further comprising a layer of a noble metal or a silicide former.
- 16. (Previously Presented) The thermal transfer material of claim 15, wherein the silicide former comprises silver, platinum or palladium.
- 17. (Previously Presented) The thermal transfer material of claim 16, wherein the silicide former is a flash layer.
- 18. (Previously Presented) The thermal transfer material of claim 1, wherein the solder material is directly deposited using electrodeposition.
- 19. (Previously Presented) A method of forming a thermal transfer material, comprising: providing a heat spreader component, wherein the heat spreader component comprises a top surface, a bottom surface and at least one heat spreader material and wherein the heat spreader component comprises a thickness of about 0.25 mm to about 6 mm;

providing at least one solder material, wherein the solder material is directly deposited onto the bottom surface of the heat spreader component; and depositing the at least one solder material onto the bottom surface of the heat spreader component.

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20. (Previously Presented 1) The method of claim 19, wherein the solder material is further coupled to a substrate.

- 21. (Previously Presented) The method of claim 20, wherein the substrate comprises silicon.
- 22. (Previously Presented) The method of claim 21, wherein the substrate is a metalized silicon die.
- 23. (Previously Presented) The method of claim 19, wherein the heat spreader component comprises a metal, metal-based material or combination thereof.
- 24. (Previously Presented) The method of claim 23, wherein the heat spreader component comprises nickel, aluminum, copper or a combination thereof.
- 25. (Previously Presented) The method of claim 23, wherein the metal-based material comprises silicon, carbon or a combination thereof.
- 26. Canceled.
- 27. (Currently Amended) The method of claim [[26]] 19, wherein the thickness is from about 1 mm to about 5 mm.
- 28. (Previously Presented) The method of claim 19, wherein the at least one solder material comprises a metal, a metal-based material or a combination thereof.
- 29. (Previously Presented) The method of claim 28, wherein the metal comprises a transition metal.
- 30. (Previously Presented) The method of claim 29, wherein the metal comprises indium, tin, lead, silver, copper, antimony, tellurium or bismuth.
- 31. (Previously Presented) The method of claim 29, wherein the metal-based material comprises an alloy.
- 32. (Previously Presented) The method of claim 31, wherein the alloy comprises indium, tin, lead, silver, copper, antimony, tellurium, bismuth or a combination thereof.

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33. (Previously Presented) The method of one of claims 30 or 31, further comprising a layer of a noble metal or a silicide former.

- 34. (Previously Presented) The method of claim 33, wherein the silicide former comprises silver, platinum or palladium.
- 35. (Previously Presented) The method of claim 34, wherein the silicide former produces a flash layer.
- 36. (Previously Presented) The method of claim 19, wherein the solder material is directly deposited using electrodeposition.